

Supplementary Information

Thickness dependence of electronic structure and optical properties of F8BT thin films

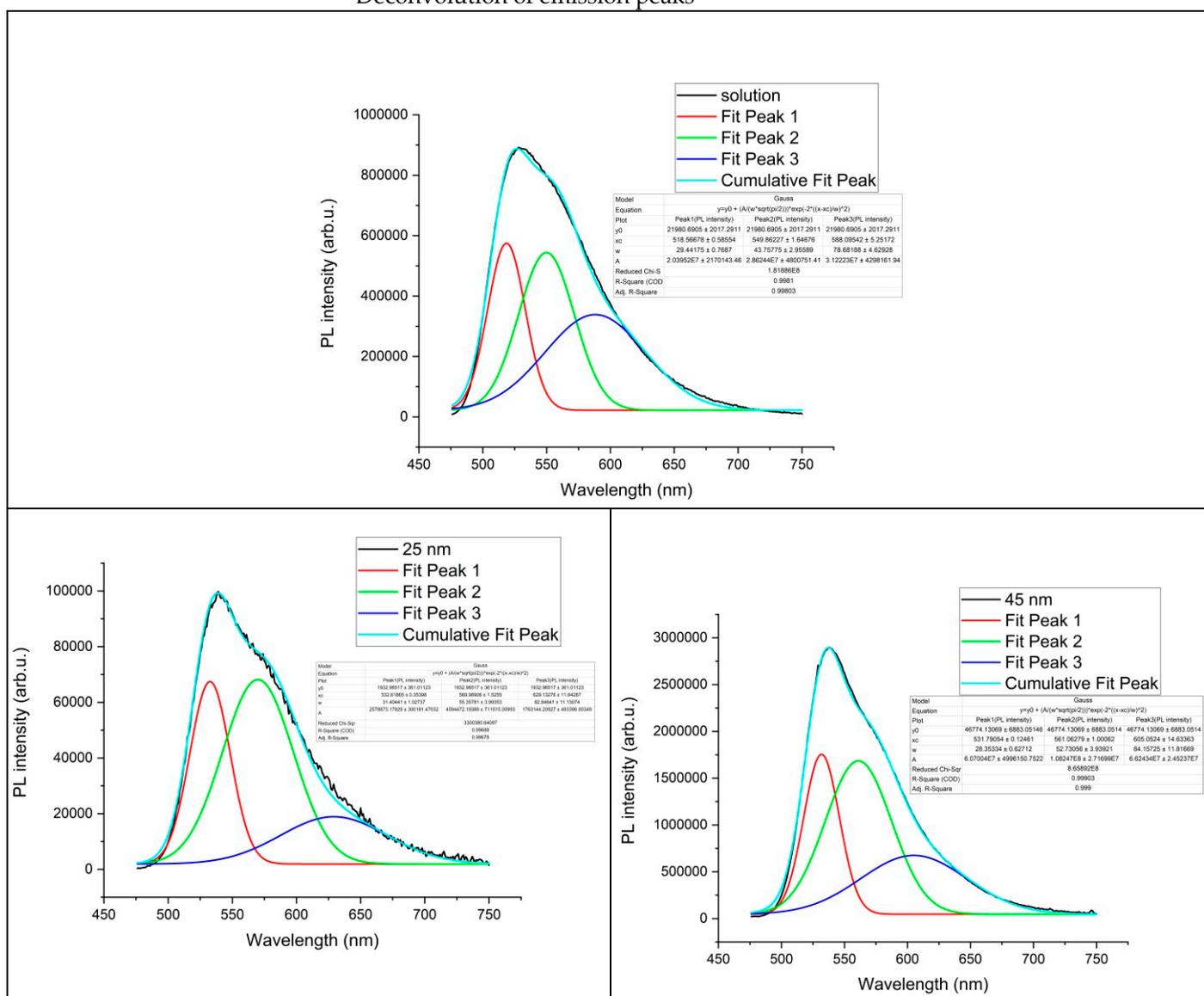
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Deconvolution of emission peaks



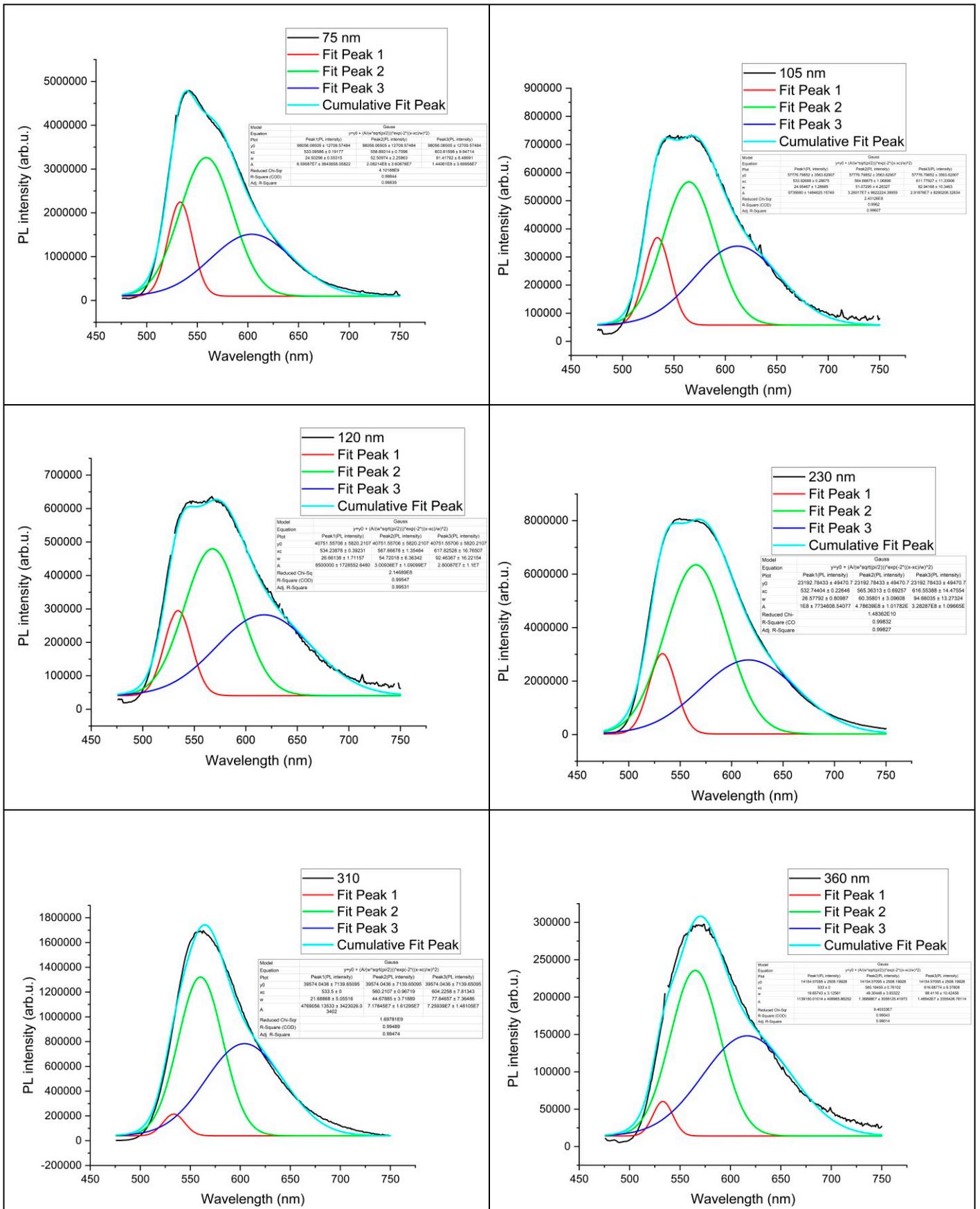


Figure S1 Deconvoluted PL emission peaks with their integrated areas.

GIWAXS Patterns

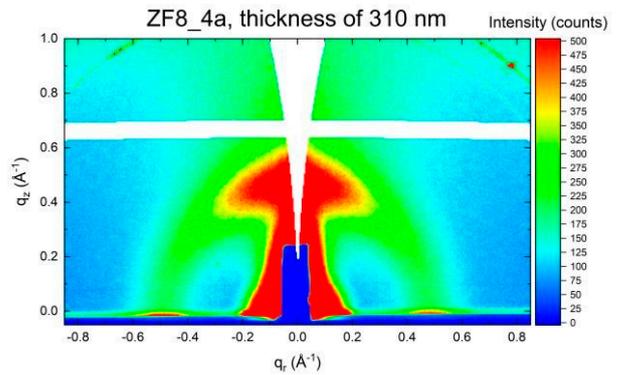
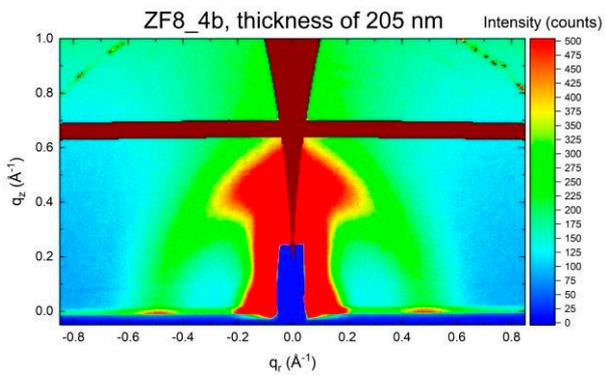
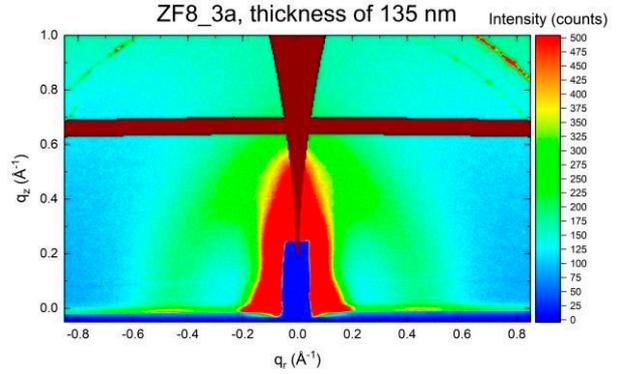
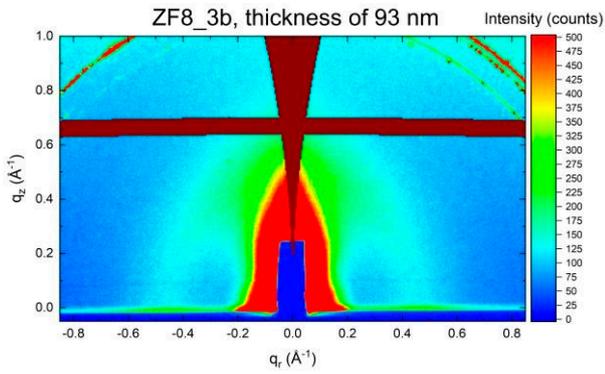
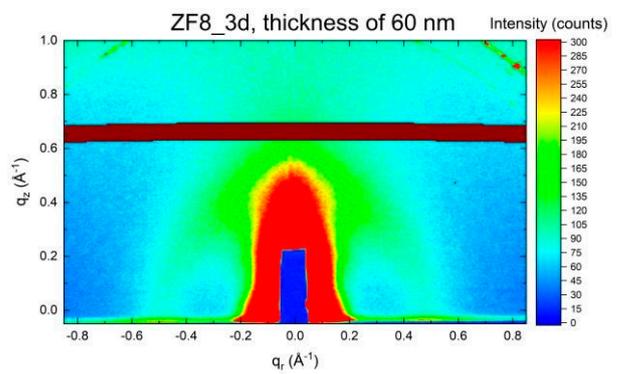
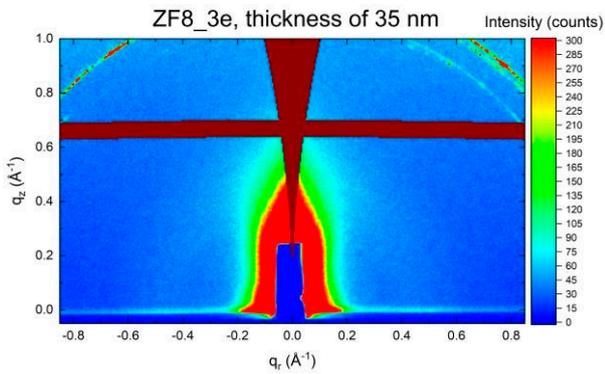
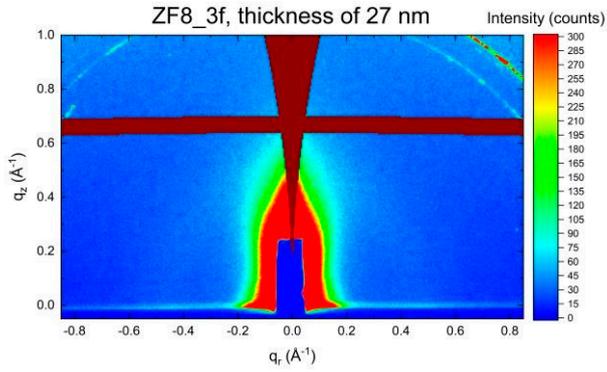


Figure S2 The GIWAXS pattern of polymer layers showing the integration area of the horizontal diffraction peaks along q_r axis (white rectangle) and the principle of integration of the vertical diffraction peak along q_z axis between $\chi = -20^\circ$ and $\chi = 20^\circ$. 18